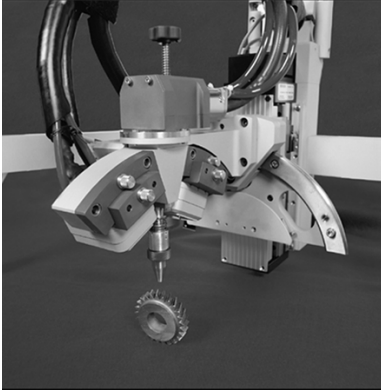


Superior Stress Measurements on Aluminum and Its Alloys



The TEC 4000 X-Ray Diffraction System

X-ray residual stress measurements made with Cu $K\alpha$ radiation at high back reflection angles on aluminum produce more precise data than measurements made with Cr $K\alpha$ radiation at lower back reflection angles. $\{511/333\}$ planes for aluminum produce a reflection at $\sim 162^\circ 2\theta$ using Cu $K\alpha$ radiation. While many other diffractometers are limited to back reflection angles no greater than $157^\circ 2\theta$, the TEC diffractometer with its position sensitive proportional counter is capable of reaching the high back reflection angle needed for aluminum planes.

There are many reasons why $\{511/333\}$ aluminum planes give better results. First, higher back reflection angles result in a larger peak shift for a given strain. Thus, the stress measurement is generally more precise when a higher back reflection angle is used. Secondly, the $\{hhh\}$ type planes (i.e., $\{333\}$) are less sensitive to preferred orientation

effects due to elastic anisotropy. Often aluminum or aluminum alloys exhibit preferred orientation that result in nonlinear d-spacing versus $\sin^2\psi$ plot. Measurements made on $\{hhh\}$ type planes often result in a linear d-spacing versus $\sin^2\psi$ plot. Linear data is preferable because it translates to more precise results.

Finally, aluminum and aluminum alloys often have relatively large grains as a result of processing. Cu $K\alpha$ radiation penetrates more deeply into aluminum than Cr $K\alpha$ radiation (at a ratio of 3.3:1). The deeper penetration means that the undesired effects of large grain size on x-ray diffraction data are minimized.

By easily providing superior measurements on aluminum and its alloys, the TEC 4000 X-Ray Diffraction System gives the quality results your company needs.

TEC's Materials Testing
Laboratory Services are



TEC
Materials Testing Division